

IT-10. Electron tomography

8 September, 17:00 - 19:00 / 9 September, 16:30 - 18:30

IT-10-P-1482

Accuracy and applications of electron-beam deposited nano-dot fiducial markers in electron tomography of rod-shaped specimens

Presenting author: **Hayashida M.**

Authors: Hayashida M., Kumagai K., Malac M., Bergen M.

IT-10-P-1681

Quantitative 360° electron tomography analysis of mesoporous hematite nanoparticles

Presenting author: **Winter B.**

Authors: Winter B., Butz B., Distaso M., Dudák M., Kočí P., Klupp Taylor R. N., Peukert W., Spiecker E.

IT-10-P-1698

The physical properties of plastic support films for 3-D transmission electron microscopy.

Presenting author: **Daraspe J.**

Authors: Daraspe J., Longo G., Kizilyaprak C., Humbel B. M.

IT-10-P-1846

A Remote Control/Observation System and an Operation Support System for the Ultrahigh Voltage Electron Tomography

Presenting author: **Yoshida K.**

Authors: Yoshida K., Nishi R., Yasuda H.

IT-10-P-1866

A memory efficient method for 3D object reconstruction with HAADF STEM depth sectioning

Presenting author: **Van Den Broek W.**

Authors: Van den Broek W., Rosenauer A., Van Aert S., Sijbers J., Van Dyck D.

IT-10-P-1875

Improving Depth of Focus in STEM Tomography using Focal Series

Presenting author: **Trepout S.**

Authors: TREPOUT S., MESSAOUDI C., BASTIN P., MARCO S.

IT-10-P-1904

Electron Holographic Tomography of Electric and Magnetic Stray Fields around Nanowires

Presenting author: **Lubk A.**

Authors: Lubk A., Wolf D., Lichte H.

IT-10-P-1980

Energy dispersive X-ray (EDX) tomography of bimetallic nanoparticles

Presenting author: **Slater T. J.**

Authors: Slater T. J., Macedo A. M., Burke M. G., O'Brien P., Camargo P. H., Haigh S. J.

IT-10-P-2061

Whole-Cell Imaging of the Budding Yeast *Saccharomyces cerevisiae* by High-Voltage Scanning Transmission Electron Tomography

Presenting author: **Tanaka N.**

Authors: Murata K., Esaki M., Ogura T., Arai S., Yamamoto Y., Tanaka N.

IT-10-P-2098

Cryo-STEM Tomography for 3D Analysis of Cell Structure

Presenting author: **Aoyama K.**

Authors: Aoyama K.

IT-10-P-2123

3D electron tomography analysis of silicon nanoparticles in SiC matrices by quantitative determination of EELS plasmon intensities

Presenting author: **Xie L.**

Authors: Xie L., Jarolimek K., Van Swaaij R., Thersleff T., Zeman M., Leifer K.

IT-10-P-2238

EELS CS tomography of FeO-Fe₃O₄ core-shell nanoparticles. An approach to recover 3D oxidation state distribution.

Presenting author: **Torruella P.**

Authors: Torruella P., Arenal R., Saghi Z., Yedra L., Eljarrat A., de la Peña F., Midgley P. A., Estradé S., Peiró F., Estrader M., López-Ortega A., Salazar-Alvarez G., Nogués J.,0,

IT-10-P-2280

Tomography in Analytical Transmission Electron Microscopy of Nanomaterials

Presenting author: **Orthacker A.**

Authors: Orthacker A., Haberfehlner G., Tändl J., Poletti M. C., Kothleitner G.

IT-10-P-2420

Tilt-less Electron Tomography

Presenting author: **Oveisi E.**

Authors: Oveisi E., Letouzey A., Lucas G., Cantoni M., Schäublin R., Fua P., Hebert C.

IT-10-P-2426

Nonlinear intensity attenuation in bright-field TEM images and its influence on tomographic reconstruction of micron-sized materials

Presenting author: **Yamasaki J.**

Authors: Yamasaki J., Mutoh M., Ohta S., Yuasa S., Arai S., Sasaki K., Tanaka N.

IT-10-P-2565

Using transmission electron tomography to unravel the structure of hybrid active layers in non volatile memory elements

Presenting author: **Girleanu M.**

Authors: Girleanu M., Nau S., Sax S., List-Kratochvil E., Soliwoda K., Celichowski G., Grobelny J., Brinkmann M., Ersen O.

IT-10-P-2603

Analysis of bainitic transformation process in Cu-Al-Mn Alloy by using an orthogonally arranged FIB-SEM for precise 3D microstructure analysis

Presenting author: **Motomura S.**

Authors: Motomura S., Hara T., Nishida M., Omori T., Kainuma R., Asahata T., Fujii T.

IT-10-P-2637

Combined 3D characterization of porous zeolites by STEM and FIB tomography

Presenting author: **Przybilla T.**

Authors: Beltrán A. M., Przybilla T., Winter B., Knoke I., Machoke A., Schwieger W., Spiecker E.

IT-10-P-2720

Prospects of Electron Holographic Tomography at Atomic Resolution : Linear Reconstruction of Dynamic Scattering using Simulated Tilt Series

Presenting author: **Krehl J.**

Authors: Krehl J., Lubk A., Lichte H.

IT-10-P-2985

Autofocus method with high-definition TV camera for ultrahigh voltage electron microscope tomography

Presenting author: **Nishi R.**

Authors: Nishi R., Kanaji A., Yoshida K., Kajimura N., Nishida T., Isakozawa S.

IT-10-P-3102

Compressed-sensing EDX Tomography of Composite Nanowires

Presenting author: **Yeoh C. S.**

Authors: Yeoh C. S., Saghi Z., Midgley P. A.

IT-10-P-3208

Electron tomography in the scanning electron microscope

Presenting author: **Ferroni M.**

Authors: Ferroni M., Migliori A., Morandi V., Ortolani L., Pezza A., Sberveglieri G.

IT-10-P-3212

Phase Contrast Cryo-Electron Tomography with a New Phase Plate

Presenting author: **Khoshouei M.**

Authors: Khoshouei M., Danev R., Gerisch G., Ecke M., Plitzko J., Baumeister W.

IT-10-P-3225

Dedicated and innovative system for tomography in the Scanning Electron Microscope

Presenting author: **Morandi V.**

Authors: Morandi V., Migliori A., Ortolani L., Pezza A., Maccagnani P., Masini L., Ferroni M., Sberveglieri G., Rossi M., Vittori-Antisari M., Vinciguerra P., Pallocca G., Del Marro M.

IT-10-P-3301

Improved Electron Tomography Image Reconstruction using Compressed Sensing based Adaptive Dictionaries.

Presenting author: **Alafeef A.**

Authors: Alafeef A., Cockshott W. P., MacLaren I., McVitie S.

IT-10-P-3455

Use your smartphone to calibrate your TEM's goniometer

Presenting author: **Wollgarten M.**

Authors: Wollgarten M., Stapel H., Garcia-Moreno F.

IT-10-P-5857

3D imaging of Si FinFETs by combined HAADF-STEM and EDS tomography

Presenting author: **Qiu Y.**

Authors: Qiu Y., Van Marcke P., Richard O., Bender H., Wilfried V.,

IT-10-P-6047

Multi-Axis Electron-Holographic Tomography

Presenting author: **Sturm S.**

Authors: Sturm S., Wolf D., Lubk A., Lichte H.